



Interfejsy Półprzewodnikowe: Formowanie i Właściwości

Indeks: **783036** Producent: **Springer** Kod producenta: **biography**

Cena: **447.31 zł**

Opis

Semiconductor Interfaces: Formation and Properties: Proceedings of the Workshop, Les Houches, France February 24–March 6, 1987: 22

Producent: Springer

- **temat:** Testing of materials, Materials science, Electronic devices & materials, Physical chemistry, Electronics engineering, Laser physics, SCIENCE / Physics / Crystallography, SCIENCE, Physics, Crystallography, TECHNOLOGY & ENGINEERING / Materials Science / Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING, Materials Science, Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING / Materials Science / Electronic Materials, Electronic Materials, SCIENCE / Chemistry / Physical & Theoretical, Chemistry, Physical & Theoretical, TECHNOLOGY & ENGINEERING / Electronics / General, Electronics, General, SCIENCE / Physics / Optics & Light, Optics & Light, TECHNOLOGY & ENGINEERING / Lasers & Photonics, Lasers & Photonics, Crystallography and Scattering Methods, Surfaces, Interfaces and Thin Film, Optical Materials, Physical Chemistry, Electronics and Microelectronics, Instrumentation, Laser, HC/Technik/Maschinenbau, Fertigungstechnik, HC, Technik, Maschinenbau, Fertigungstechnik, HC/Chemie/Physikalische Chemie, Chemie, Physikalische Chemie, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, Physik, Astronomie, Elektrizität, Magnetismus, Optik, development;diffraction;electronic properties;microscopy;optical properties;optoelectronic devices;production;semiconductor;spectroscopy;transistor, Engineering applications of electronic, magnetic, optical materials, SCIENCE / Chemistry / Physical & Theoretical, SCIENCE / Physics / Crystallography, SCIENCE / Physics / Optics & Light, Science/Chemistry - Physical & Theoretical, Science/Physics - Crystallography, Science/Physics - Electricity, Science/Physics - Optics & Light, TECHNOLOGY & ENGINEERING / Electronics / General, TECHNOLOGY & ENGINEERING / Electronics / Microelectronics, TECHNOLOGY & ENGINEERING / Lasers & Photonics, TECHNOLOGY & ENGINEERING / Materials Science / Electronic Materials, TECHNOLOGY & ENGINEERING / Materials Science / Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING / Optics, Technology & Engineering/Electronics - Microelectronics, Technology & Engineering/Lasers & Photonics, Technology & Engineering/Materials Science - Electronic Materials, Technology & Engineering/Materials Science - Thin Films, Surfaces & Interfaces, Technology & Engineering/Optics, Condensed matter physics (liquid state & solid state physics), Electronic devices & materials, Electronic devices & materials, Electronics engineering, Laser physics, Materials science, Optical physics, Physical chemistry, Testing of materials, Elektronik, Engineering applications of electronic, magnetic, optical materials, Laserphysik, Materialwissenschaft, Physikalische Chemie, Technische Anwendung von elektronischen, magnetischen, optischen Materialien, Werkstoffprüfung, HC/Chemie/Physikalische Chemie, HC/Physik, Astronomie/Elektrizität, Magnetismus, Optik, HC/Technik/Elektronik, Elektrotechnik, Nachrichtentechnik, HC/Technik/Maschinenbau, Fertigungstechnik, Hardcover, Softcover / Technik/Maschinenbau, Fertigungstechnik
- **wiązący:** paperback
- **język:** english, english, english
- **waga przedmiotu:** 1050 grams

- **strony:** 400
- **słowo kluczowe tematu:** Development; diffraction; Electronic Properties; microscopy; Optical Properties; Optoelectronic devices; production; Spectroscopy; Transistor, Germany, Non-Fiction, SCI/TECH, Science/Math, development; diffraction; electronic properties; microscopy; optical properties; optoelectronic devices; production; semiconductor; spectroscopy; transistor, development; diffraction; electronic properties; microscopy; optical properties; optoelectronic devices; production; semiconductor; spectroscopy; transistor
- **marka:** Springer
- **kod unspsc:** 55101500
- **kod podmiotu:** TJF, TGMM, PHJL, TGM, PNR, TGMM, TGMT, SCI013050, SCI016000, SCI053000, SCI013050, SCI016000, SCI021000, SCI053000, TEC008000, TEC008070, TEC019000, TEC021020, TEC021040, TEC030000, TEC008070, TEC019000, TEC021020, TEC021040, TEC030000, PHFC, TJFD, TJFD, TJF, PHJL, TGM, PHJ, PNR, TGMT, 1655, 1643, 1684, 1682, 1682
- **grupa docelowa:** General/trade
- **tom:** 22
- **Liczba przedmiotów:** 1
- **numer części:** biography
- **kolor:** White
- **waga opakowania przedmiotu:** 1.5 pounds
- **wydanie:** 1987
- **numer seryjny:** 22
- **zewnętrznie przypisany identyfikator produktu:** 364272969X, 9783642729690, 09783642729690
- **producent:** Springer
- **tytuł serii:** Springer Proceedings in Physics, 22
- **gatunek muzyczny:** Testing of materials, Materials science, Electronic devices & materials, Physical chemistry, Electronics engineering, Laser physics, SCIENCE, Physics, Crystallography, TECHNOLOGY & ENGINEERING, Materials Science, Thin Films, Surfaces & Interfaces, TECHNOLOGY & ENGINEERING, Materials Science, Electronic Materials, SCIENCE, Chemistry, Physical & Theoretical, TECHNOLOGY & ENGINEERING, Electronics, General, SCIENCE, Physics, Optics & Light, TECHNOLOGY & ENGINEERING, Lasers & Photonics, HC, Technik, Maschinenbau, Fertigungstechnik, HC, Chemie, Physikalische Chemie, HC, Technik, Elektronik, Elektrotechnik, Nachrichtentechnik, HC, Physik, Astronomie, Elektrizität, Magnetismus, Optik, Testing of materials, Materials science, Engineering applications of electronic, magnetic, optical materials, Physical chemistry, Electronics engineering, Laser physics
- **Data publikacji:** 2011-12-06T00:00:01Z
- **numer wydania:** 1
- **nazwa przedmiotu:** Semiconductor Interfaces: Formation and Properties: Proceedings of the Workkshop, Les Houches, France February 24–March 6, 1987: 22
- **data premiery:** 2011-12-06T00:00:01Z
- **data uruchomienia strony produktu:** 2012-08-11T00:39:34.308Z

Parametry

Typ	papierowa
Język	angielski
Rok wydania	1987